

Addressing High Precision Automated Optical Inspection Challenges with Unique 3D Technology Solution

John Hoffman
CyberOptics Corporation
jhoffman@cyberoptics.com

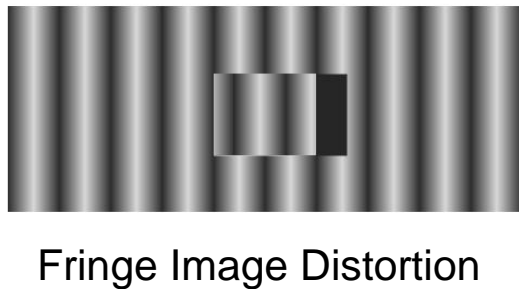
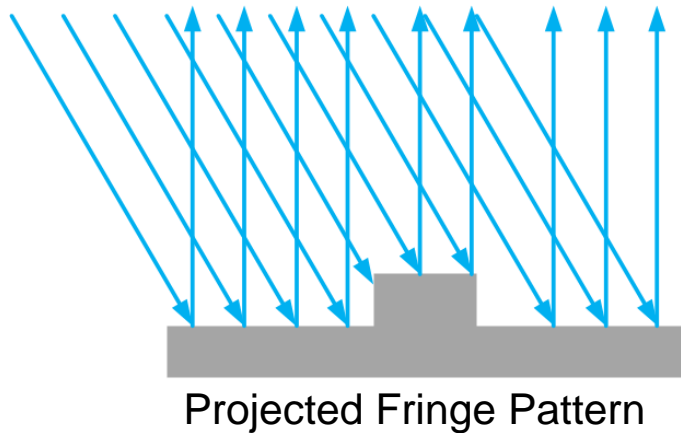
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Outline/Agenda

- **Phase Profilometry**
- **SMT Assembly Imaging Challenges**
- **3D Technology Solution**
- **Results**
- **Conclusions**
- **Q & A**

Phase Profilometry



$$I = I_0 R(1 + m \sin(2\pi f_x + \phi_0))$$

Advantages

- Combination of speed and accuracy when properly architected
- Micron level accuracy

Challenges

- Tall components
- Highly reflective surfaces
- Odd shapes
- Inspection speed

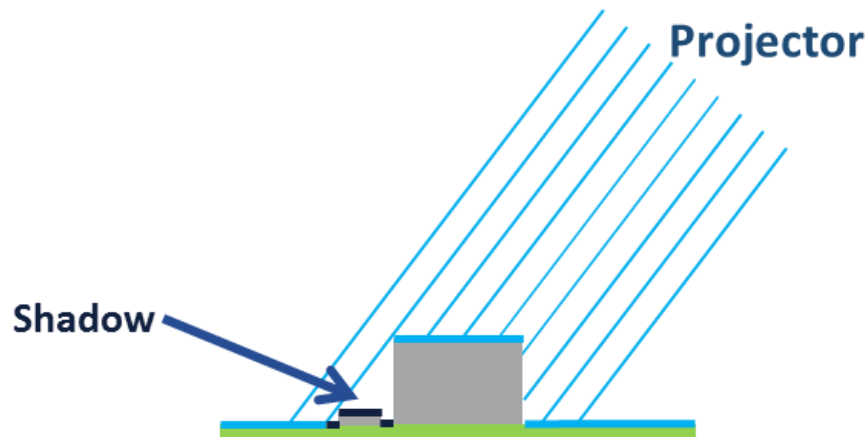


SMT Assembly Imaging Challenges

- Tall Components
- Highly Reflective Surfaces
- Odd Shapes
- Inspection Speeds

Tall Component Challenges

Small components and features are shadowed



- Small passives next to taller RF shields
- SMT assemblies with THT components
- SMT connector leads shadowed by other components and connector body

Sufficient range to measure above 10mm



Challenges Imaging SMT Assemblies

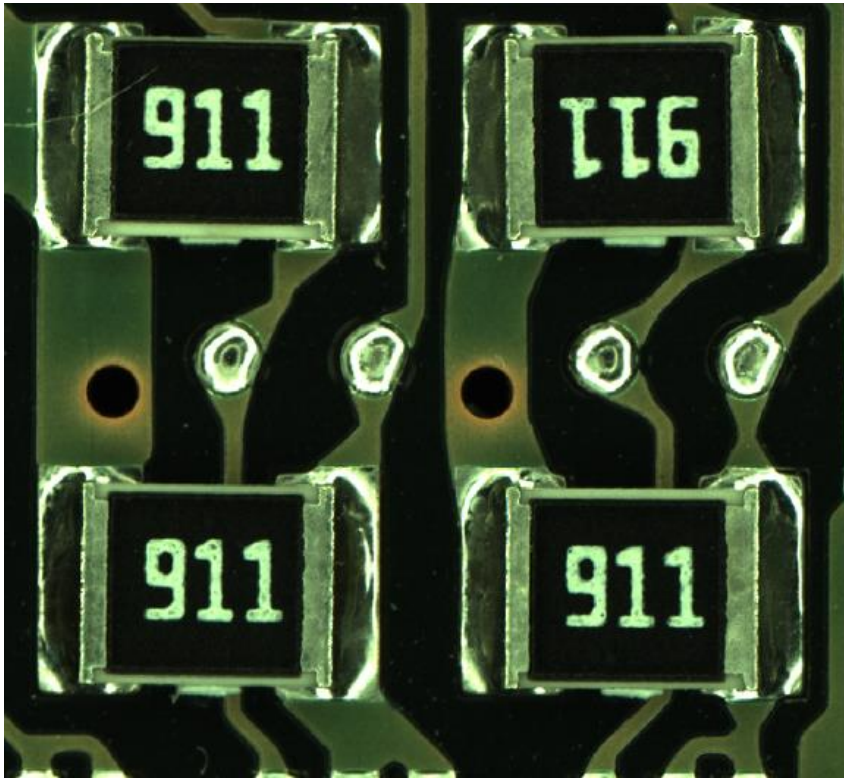
- Tall Components

- Highly Reflective Surfaces

- Odd Shapes

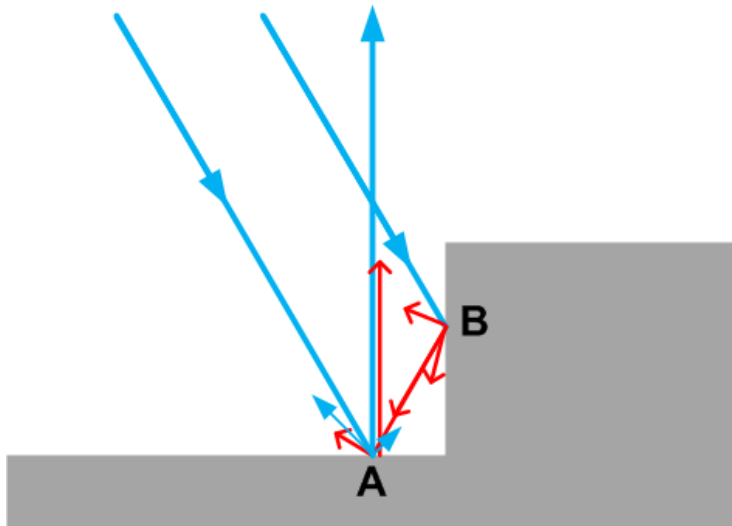
- Inspection Speeds

Typical PCB with Highly Reflective Solder Joints

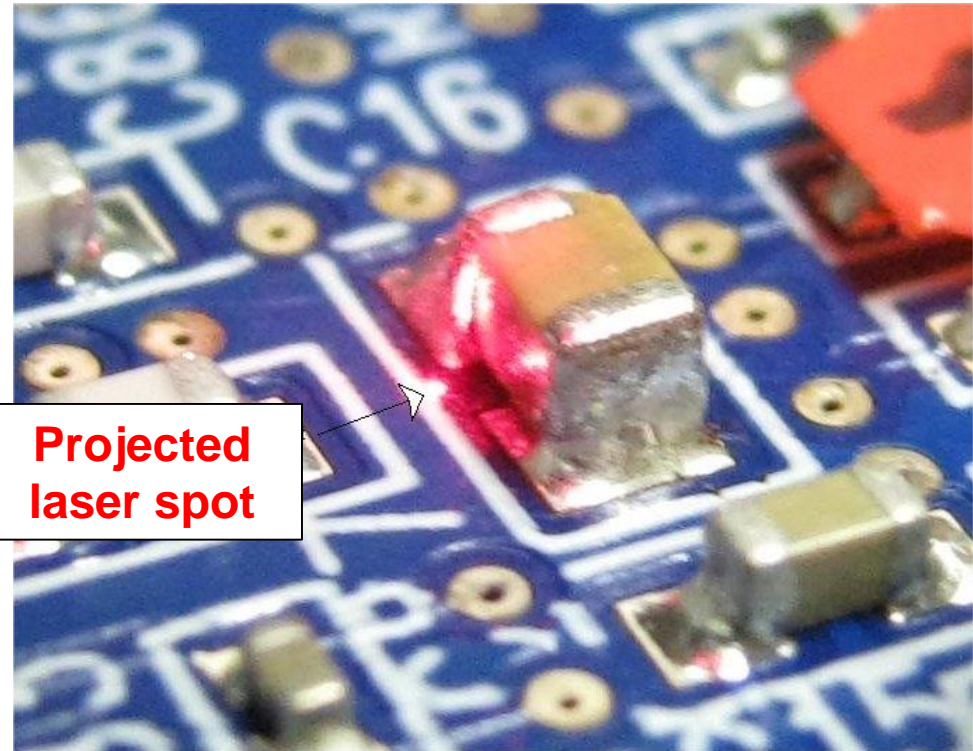


- Some mirror-like surfaces will cause camera saturation
- Other mirror-like surfaces will reflect light completely away from camera
- Severity of multiple reflections increase with highly reflective surfaces

Multiple Reflections



**Observed Intensity at Point A
is Altered by Scattered
Reflection at Point B**



**Laser Experiment to Visualize
Multiple Reflections**



Challenges Imaging SMT Assemblies

- Tall Components
- Reflective Surfaces
- Odd Shapes
- Inspection Speeds

Odd Shapes

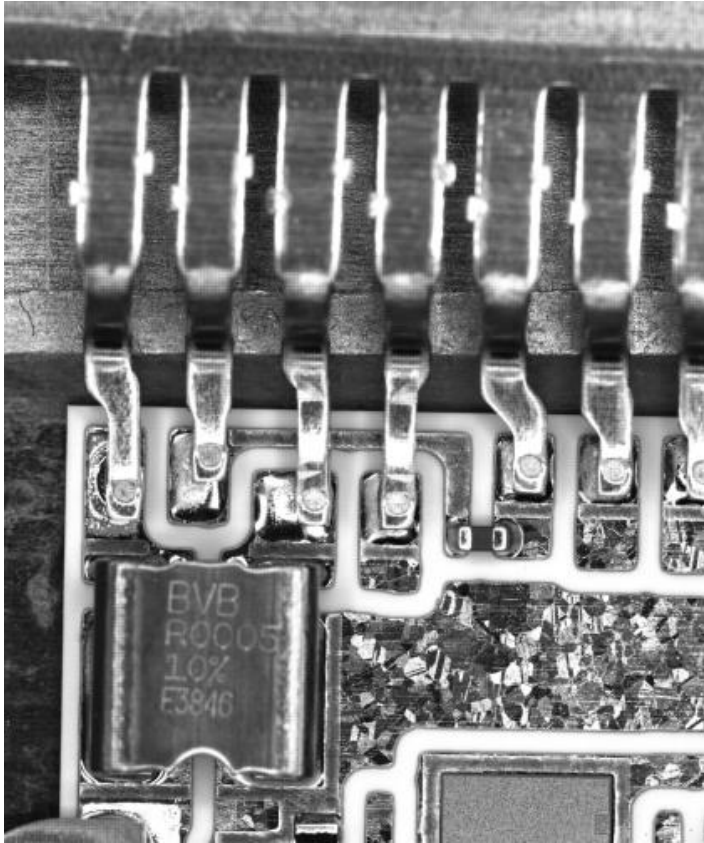


Image data in 2D

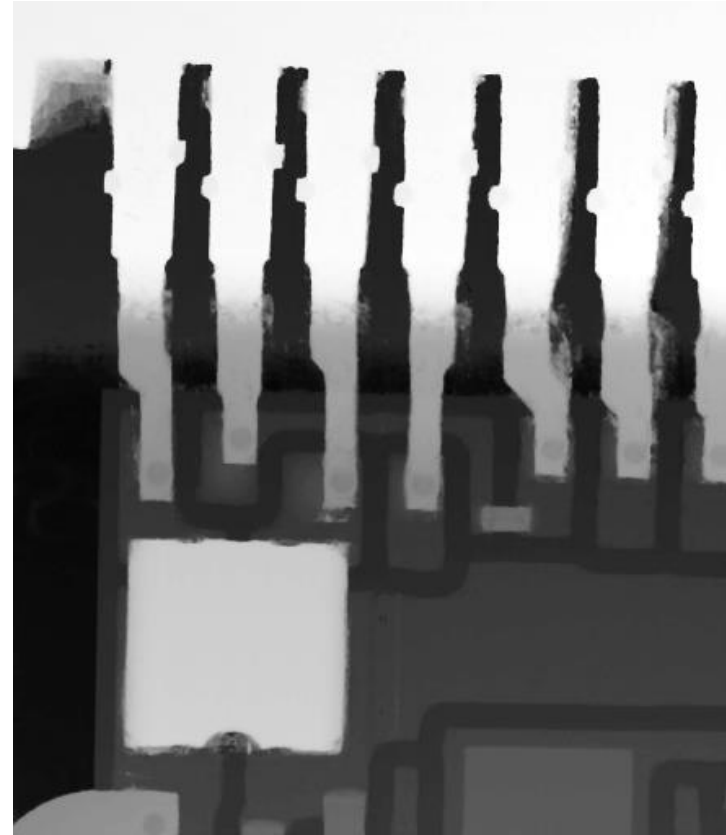


Image data in 3D



Challenges Imaging SMT Assemblies

- Tall Components
- Reflective Surfaces
- Odd Shapes
- Inspection Speeds

Inspection Speed

- Image acquisition – 10X more images
 - Traditional 2D Image technology - up to 2-3 images with different illumination at each FOV
 - 3D systems require all of the 2D imagery plus
 - At least 6, and likely more, images from each projector (4x)
 - RGB images if using monochrome imaging detector for each illumination type (+3x)



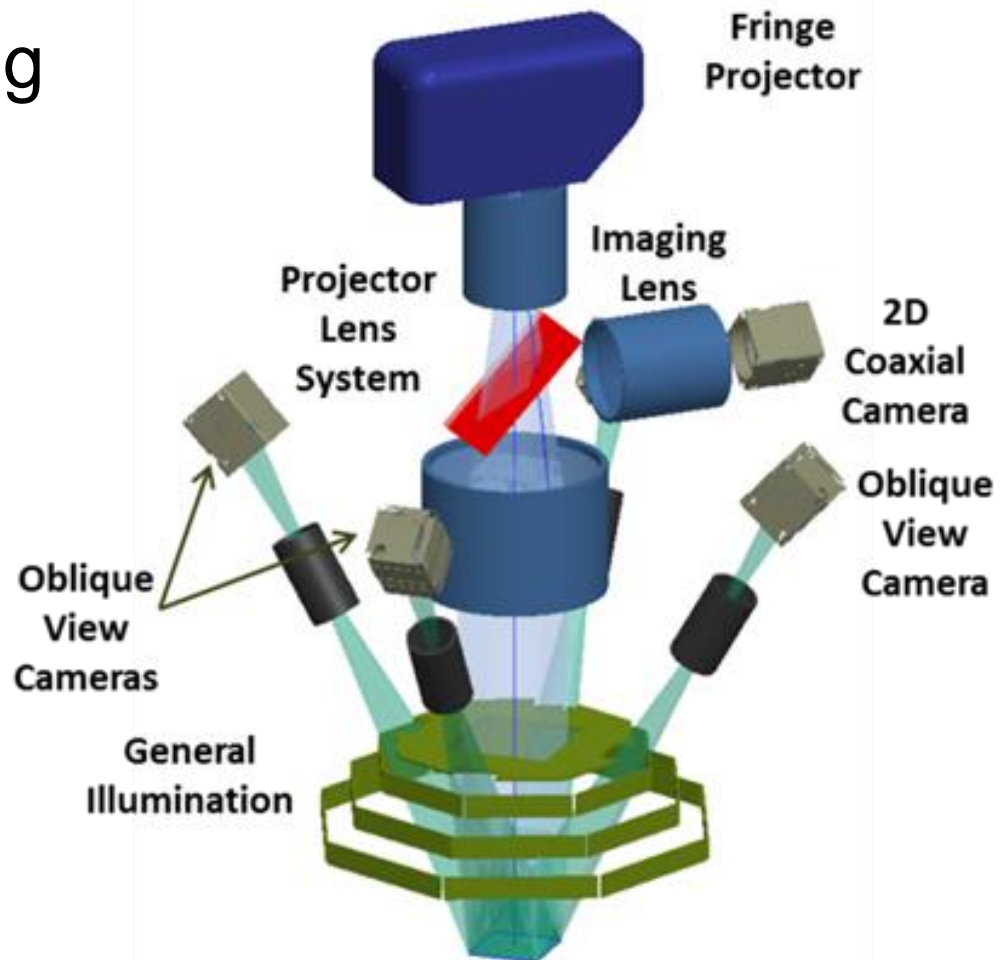
Inspection Speed

- Image Processing

- ☐ All existing 2D inspection
- ☐ Plus processing to obtain 3D height information
- ☐ Plus additional 3D task processing

Sensing Architecture to Overcome Inspection Challenges

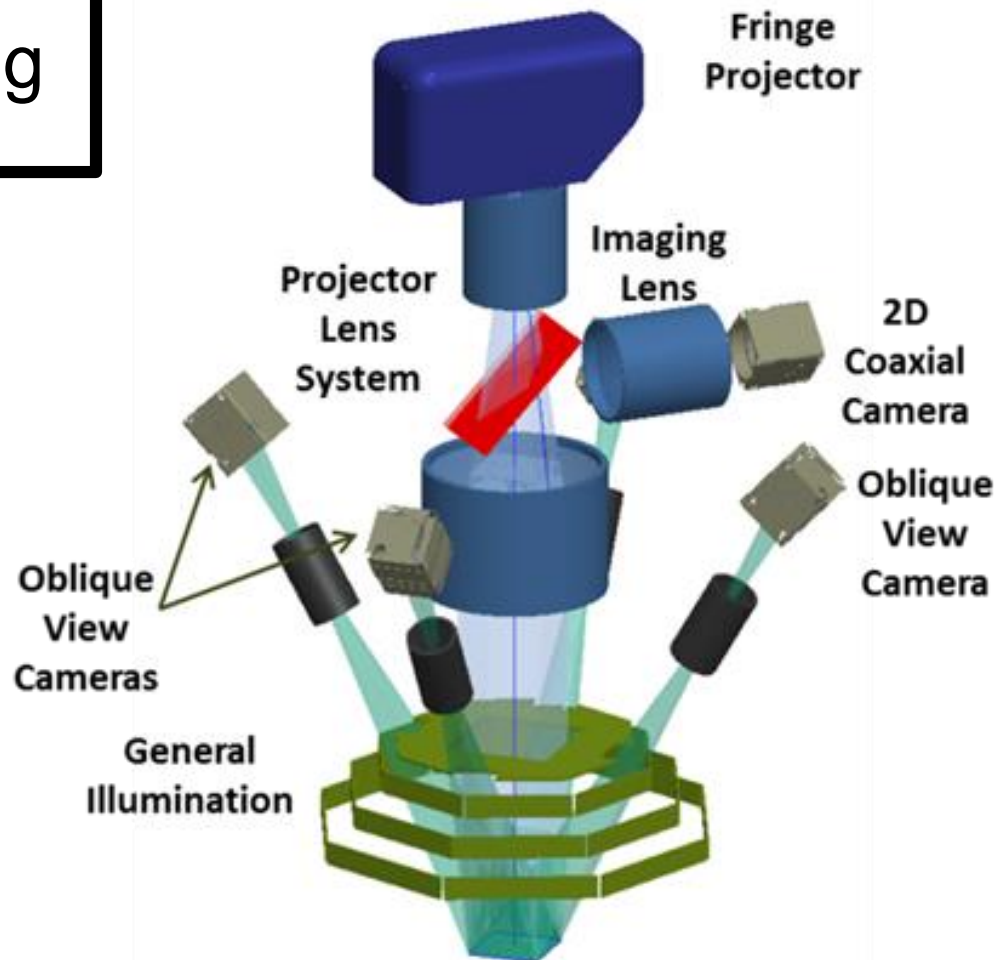
- Parallel 3D Sensing
- Flexible fringe projector
- Model accurate height information



Sensing Architecture to Overcome Inspection Challenges

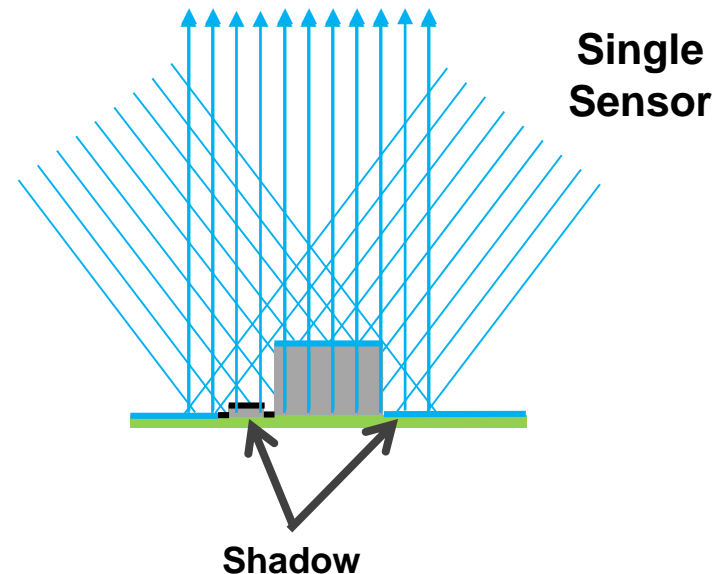
■ Parallel 3D Sensing

- Flexible fringe projector
- Model accurate height information



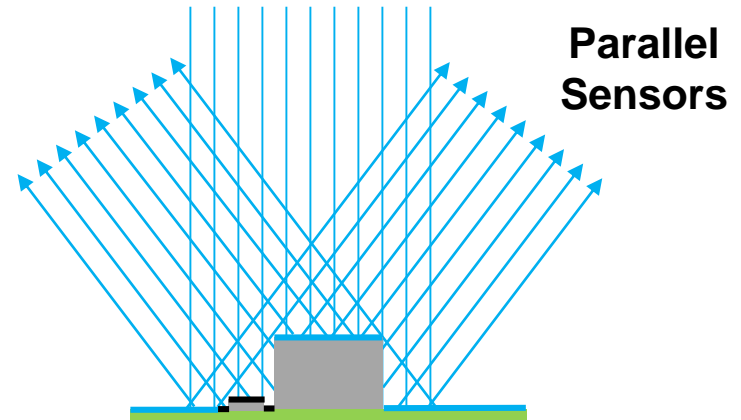
Single 3D Sensing

- With AOI a shadow effect is inevitable
- Single sensor system uses multiple sources to obtain necessary information



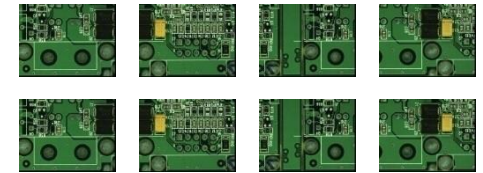
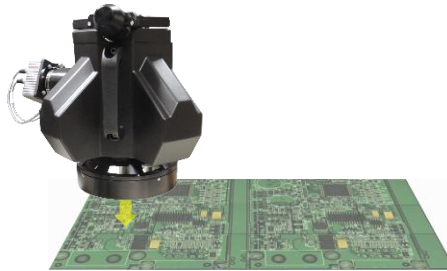
Parallel 3D Sensing

- Multiple sensor can simultaneously obtain all necessary information in parallel
- Increases potential speed

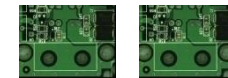


Advantage of Parallel Architecture is Acquisition Speed

- Parallel 3D Sensing



- Single Sensor

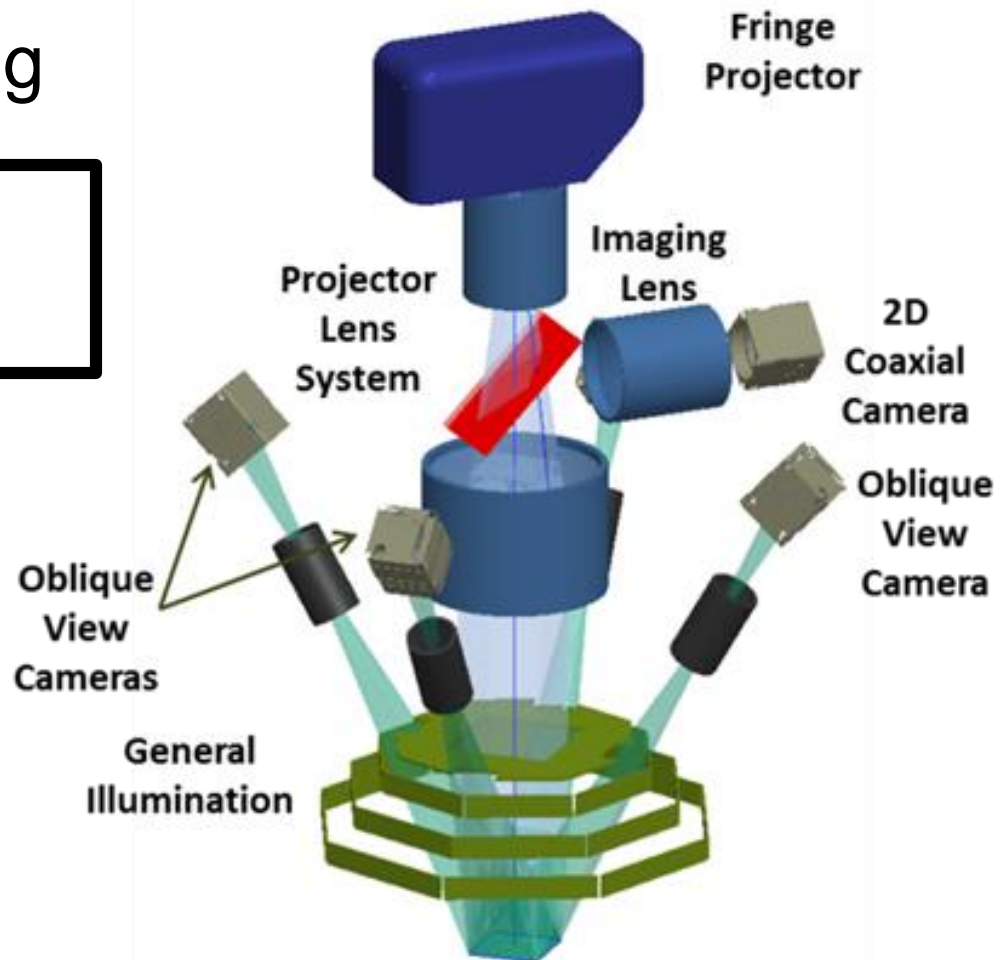


Sensing Architecture to Overcome Inspection Challenges

- Parallel 3D Sensing

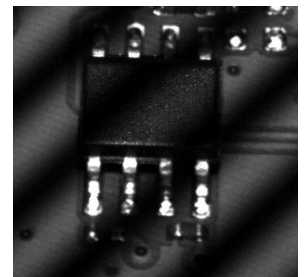
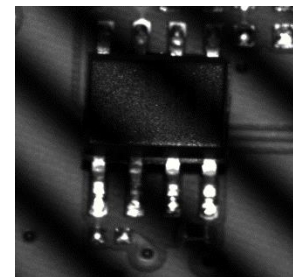
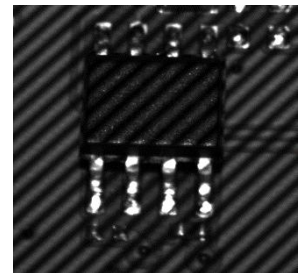
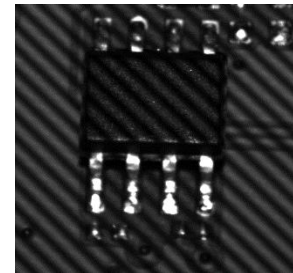
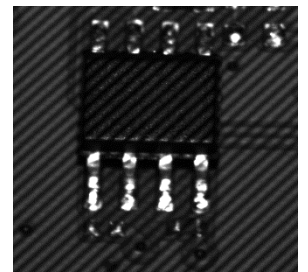
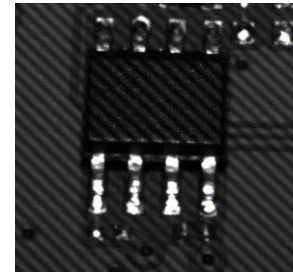
- Flexible fringe projector

- Model accurate height information



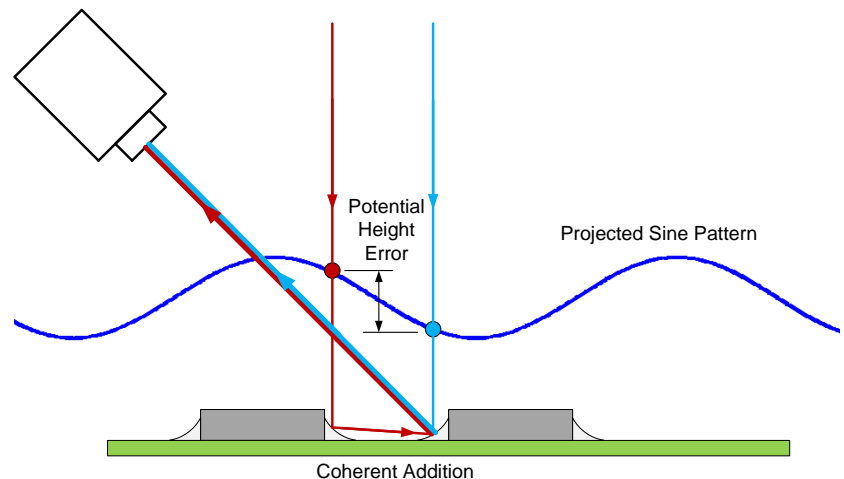
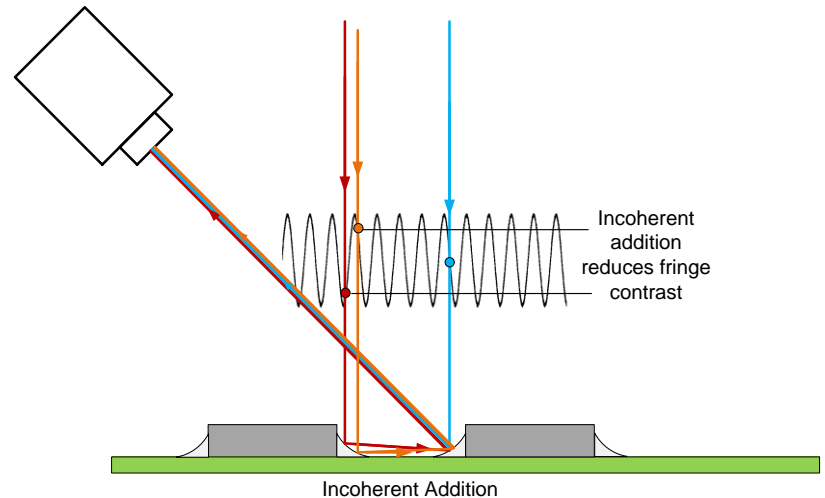
Flexible Illumination

- Programmable 3D illumination projector using DLP or LCoS technology
 - Any pattern in any direction
 - Wide and varying height range suited to application

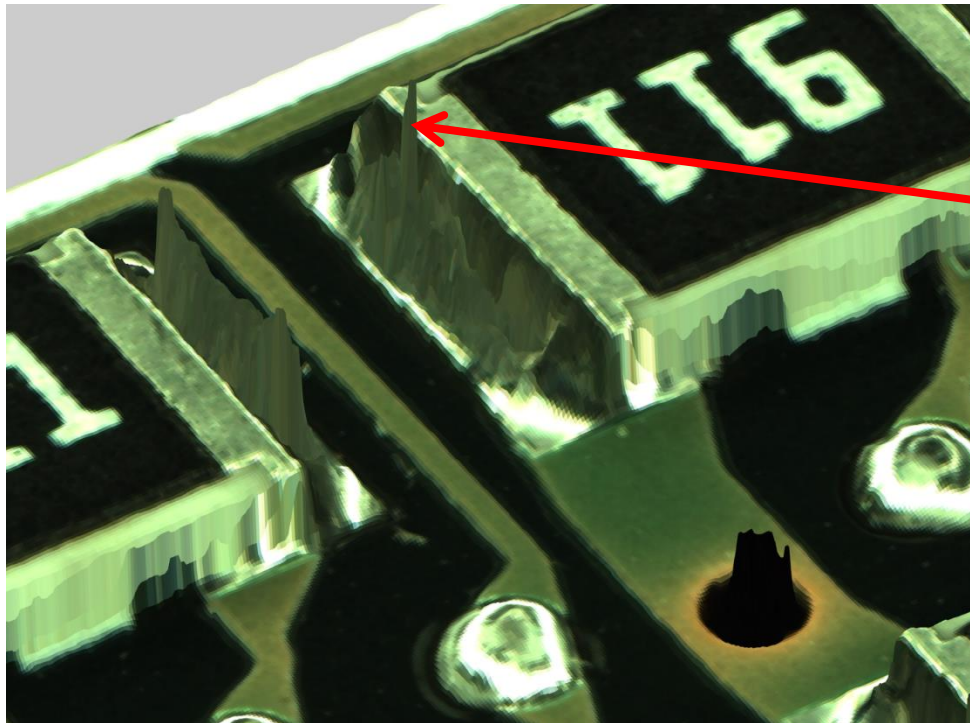


Detecting and Suppressing Multiple Reflections

- Multiple reflections do occur, but provide different return at
 - Different projection frequencies
 - Different camera angles
- Used to separate the primary reflections from the secondary

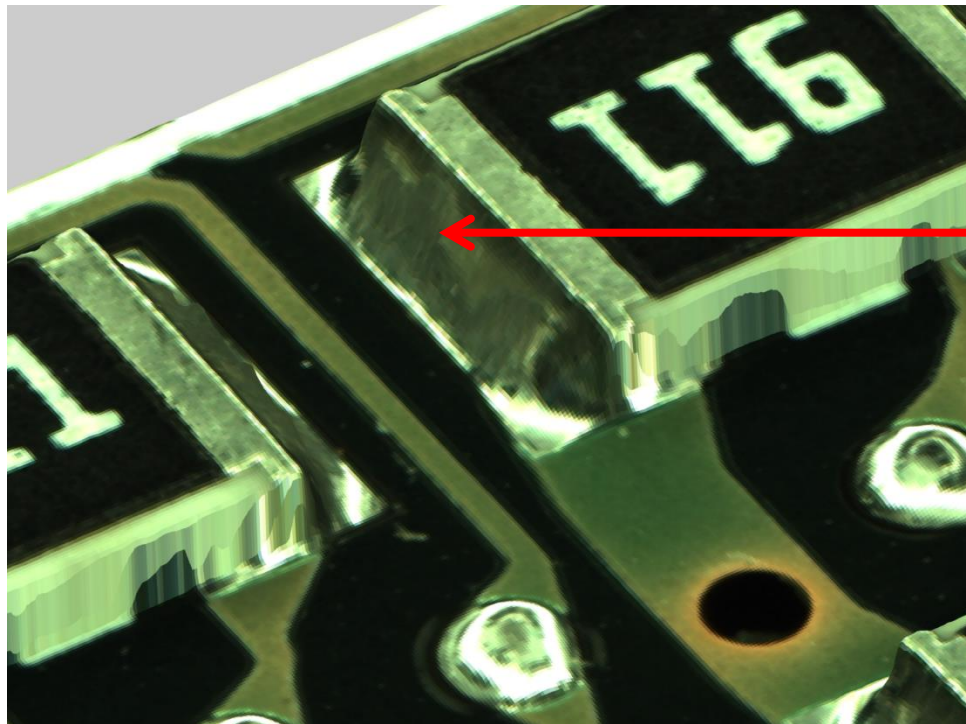


Without Multiple Reflection Suppression Techniques



**Height
Spikes**

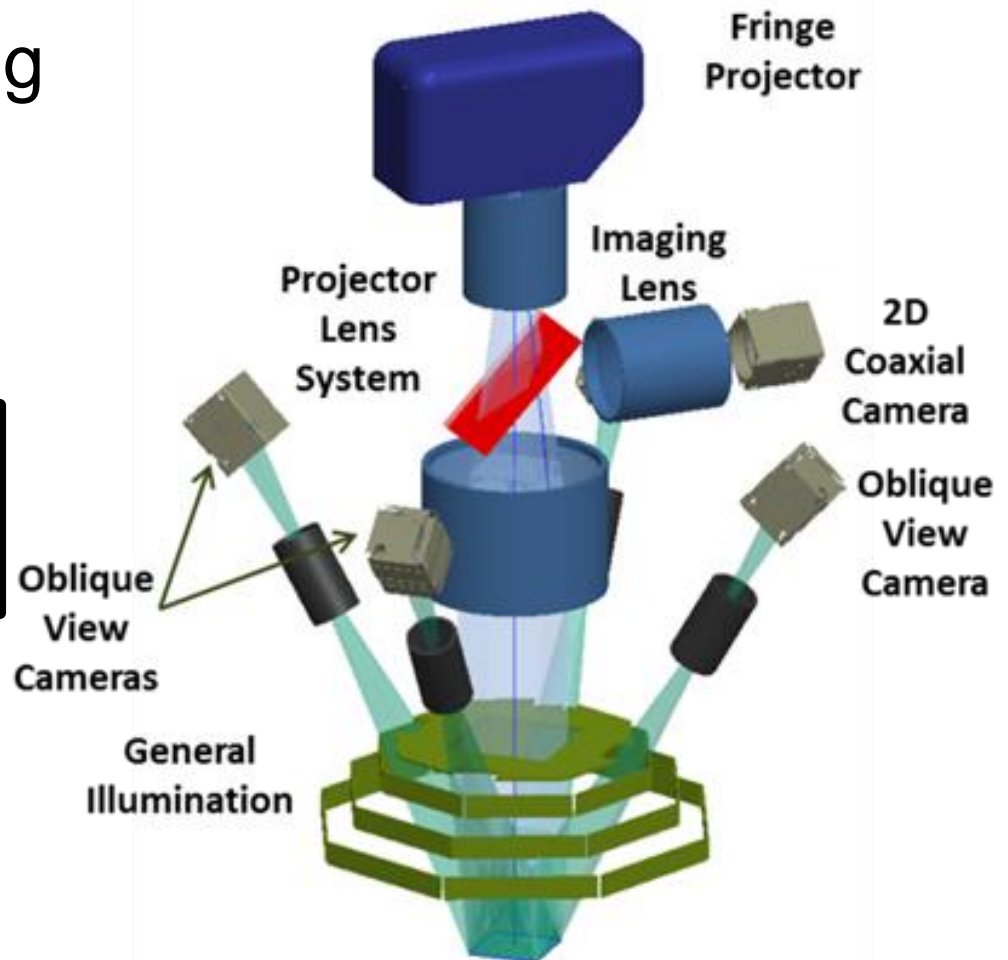
With Multiple Reflection Suppression Techniques



**Height
Spikes
Eliminated**

Sensing Architecture to Overcome Inspection Challenges

- Parallel 3D Sensing
- Flexible fringe projector
- Model accurate height information



PCA Learns Normal to Detect Abnormal

Original



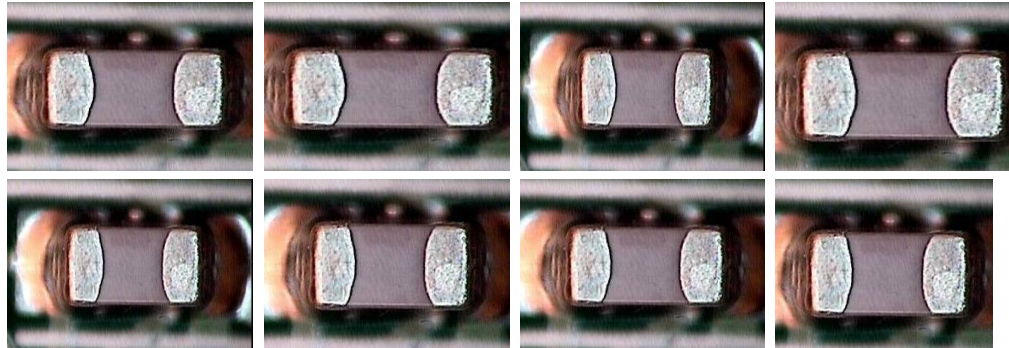
5% Larger



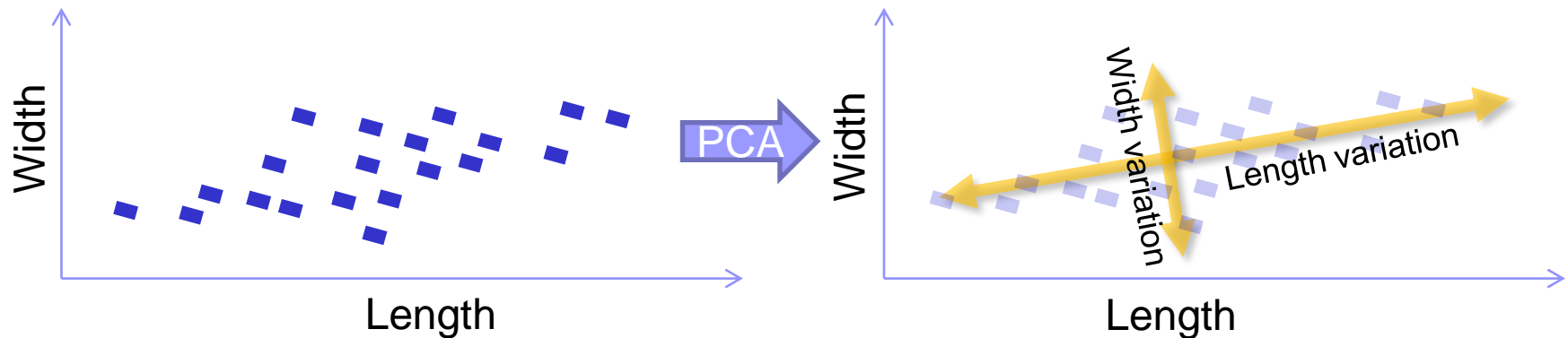
5% Larger Eye Only



Principal Component Analysis (PCA) Basic Concept



For example, resistors with only differences in width and length

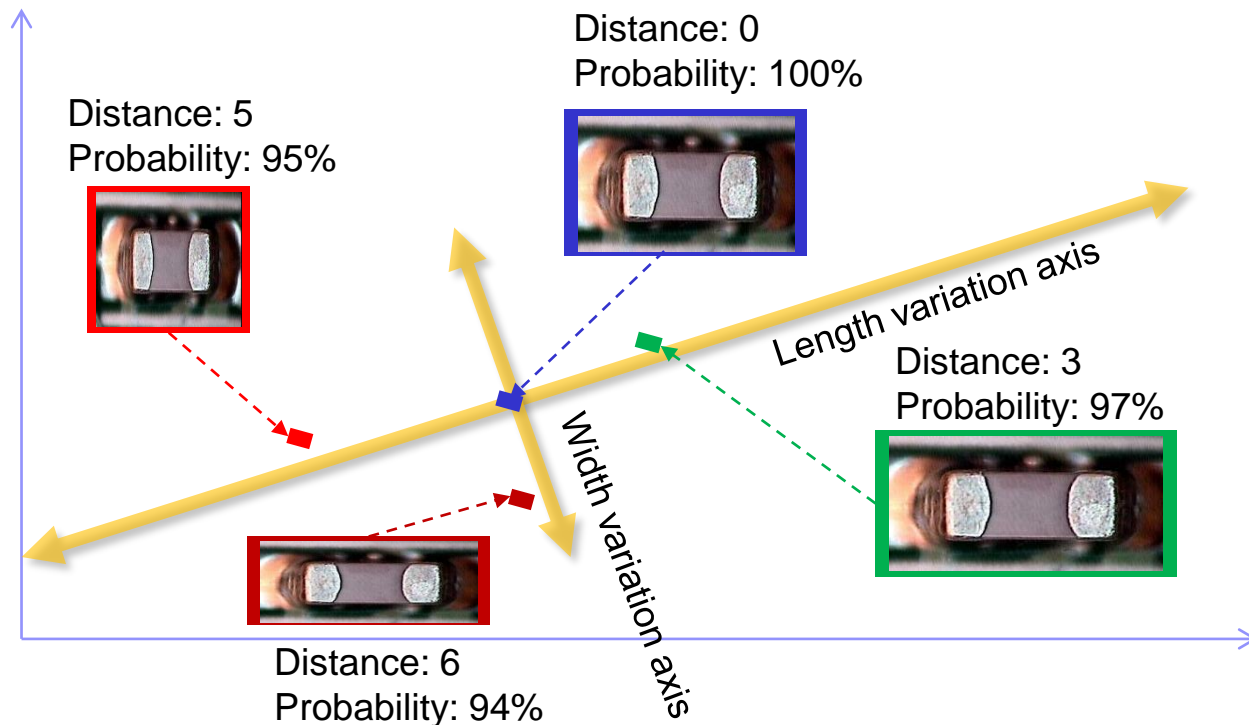
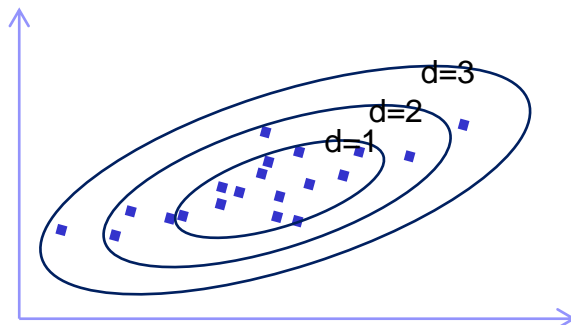


Principal **C**omponent **A**nalysis to discover key variation axes

Principle Component Analysis Basic Concept

Inspection

- ✓ Calculate how far the new sample is from the model based on **Mahalanobis distance**



3D Image Information

- Modeling using height information instead of intensity information

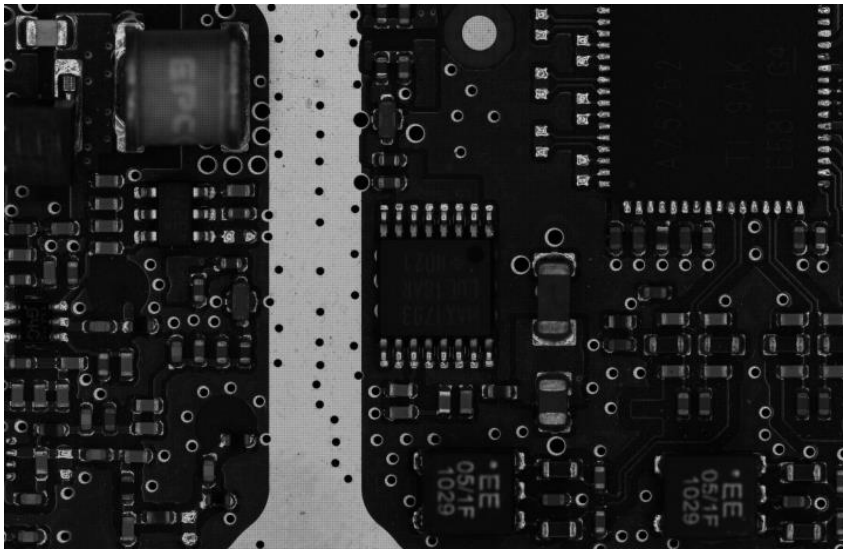


Image data in 2D

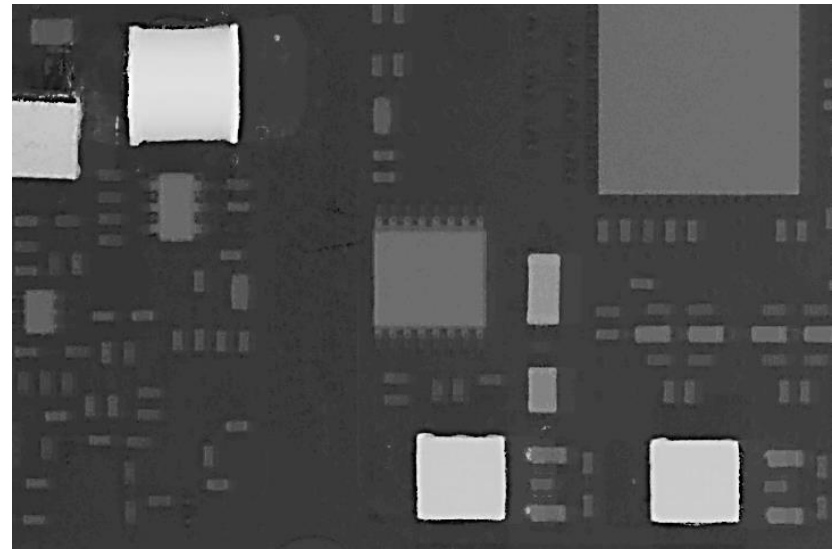
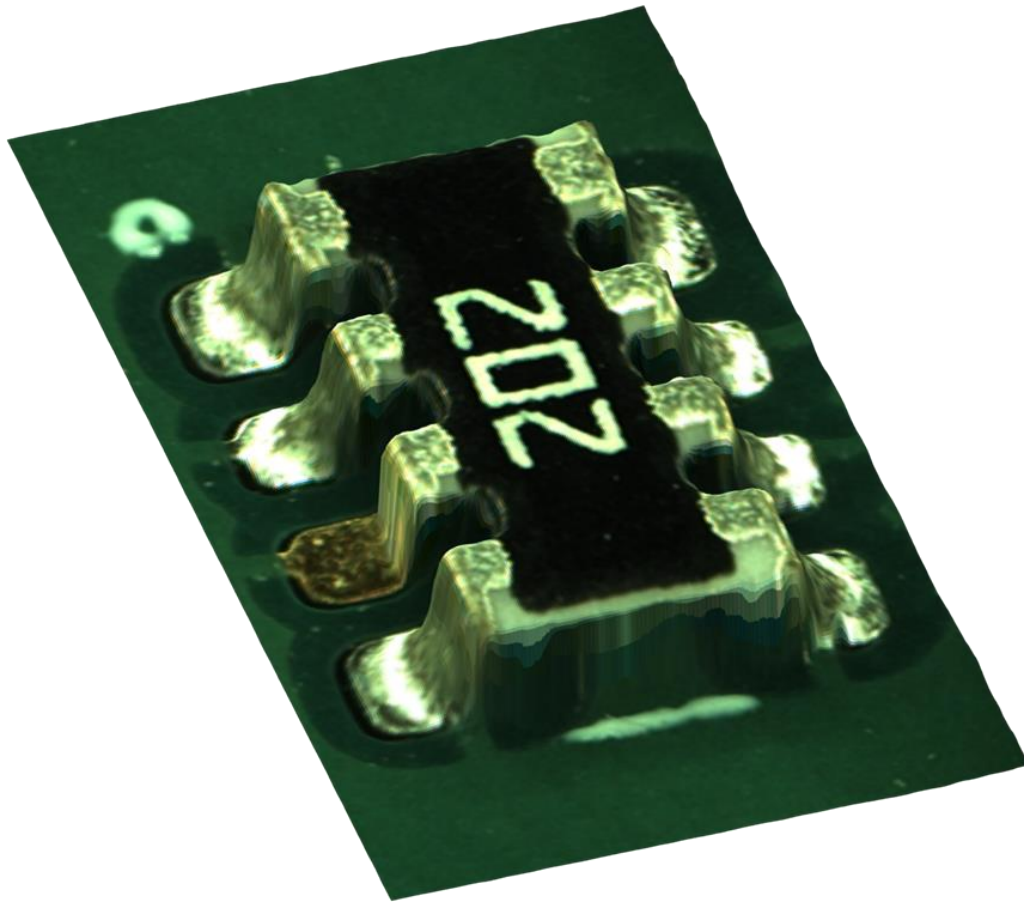


Image data in 3D

Results





Conclusion

- There are many inspection challenges for 3D AOI systems to overcome
- Technological architecture enables the best solutions to these challenges
- Understanding how an inspection system accomplishes inspection is key to choosing the right system for your needs